Powder Diffraction

Deane K. Smith	Editorial: Good-Bye Old Friends	229
Richard N. Rose	Sigmund Weissmann Pioneering X-ray Crystallographer: From insights into the "pathology of structure" (lattice defects) and physical metallurgy came one of the first laboratories for Materials Science—and a life-long association with the PDF	230
P. L. Wallace, S. Weissmann, M. H. Mueller, L. D. Calvert, and R. Jenkins	The new ICDD Metals and Alloys Indexes: Usefulness and potentialities	239
Karimat El-Sayed, Z. K. Heiba	Quantitative phase analysis from X-ray powder diffraction data using a two-stage method	246
E. A. Judson, D. N. Hill, R. A. Young, J. R. Cagle, W. J. Lackey, W. B. Carter, and E. K. Barefield	An analysis of preferred orientation in $YBa_2Cu_3O_{7-x}$ superconducting films deposited by CVD on single-crystal and polycrystalline substrates	250
Fengchao Liu	Influence of thermal expansion on the lattice parameter of silicon	260
C. L. Lengauer, G. Giester, and E. Irran	$KCr_3(SO_4)_2(OH)_6$: Synthesis, characterization, powder diffraction data, and structure refinement by the Rietveld technique and a compilation of alunite-type compounds	
H. Toraya, T. Ochiai	Refinement of unit-cell parameters by whole-powder-pattern fitting technique	272
Winnie Wong-Ng, Lawrence P. Cook	A review of the crystallography and crystal chemistry of compounds in the BaO-CuO _x system	280
	International Report	290
	Calendar of Meetings	290
	Commercial Announcements	291
	Volume 9, 1994 Contents	292
	Index to Volume 9	
	Summary of the Physics and Astronomy Classification Scheme	294
	PACS Headings Used in the Present Index	295
	Subject Index	296
	Author Index	299



Volume 9 Number 4 December 1994Powder DiffractionAn international journal of materials characterization

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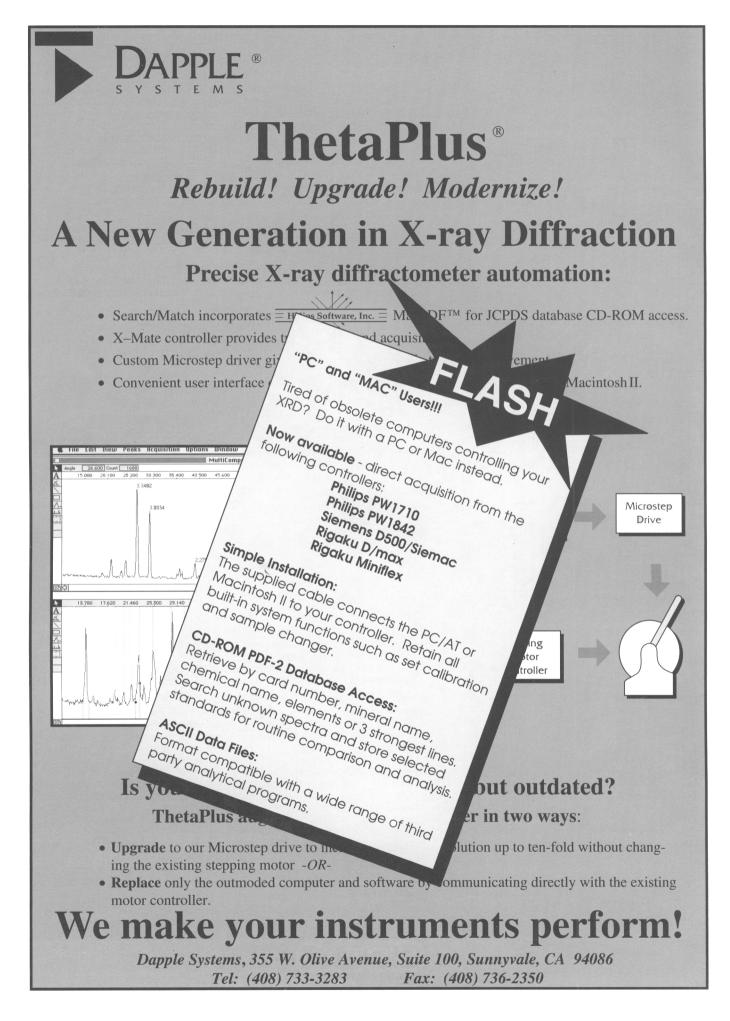


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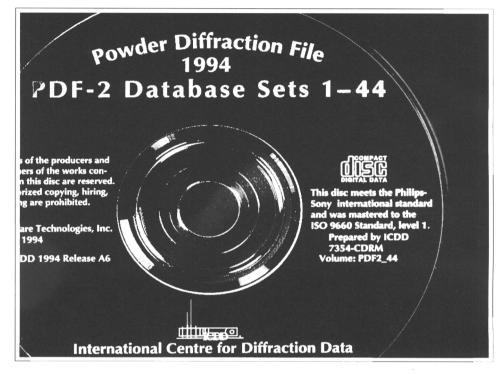
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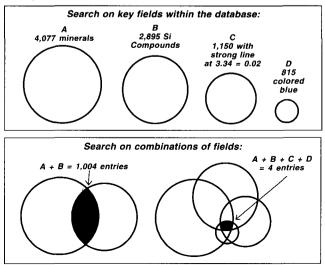
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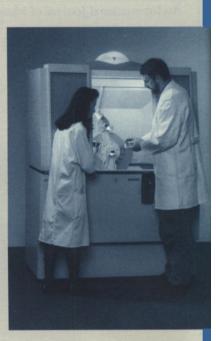
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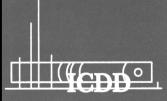
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